


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575789	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Quang T Van	<b>Art Unit</b>  3742

SEARCHED			
Class	Subclass	Date	Examiner
219	756,757,681	7/1/2010	QV
126	21A,299R,299D,275E,273A	7/1/2010	QV

SEARCH NOTES		
Search Notes	Date	Examiner
East search and Inventor check	7/1/2010	QV

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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